

N-Ch MOSFET

General Description

The WSD30150ADN56 is the highest performance trench N-Ch MOSFET with extreme high cell density , which provide excellent R_{DSON} and gate charge for most of the synchronous buck converter applications .

The WSD30150ADN56 meet the RoHS and Green Product requirement , 100% EAS guaranteed with full function reliability approved.

Features

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- 100% EAS Guaranteed
- Green Device Available

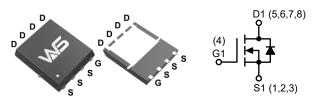
Product Summery

BV _{DSS}		Ι _D
30V	2.2mΩ	145A

Applications

- High Frequency Point-of-Load Synchronous Buck Converter
- Networking DC-DC Power System
- Power Tool Application

DFN5X6-8L Pin Configuration



Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V _{DS}	Drain-Source Voltage	30	V
V _{GS}	Gate-Source Voltage	±20	V
I₀@T₀=25℃	Continuous Drain Current, V _{GS} @ 10V ^{1,7}	145	A
I _D @T _C =100℃	Continuous Drain Current, V _{GS} @ 10V ^{1,7}	75	A
I _{DM}	Pulsed Drain Current ²	310	A
EAS	Single Pulse Avalanche Energy ³	372	mJ
I _{AS}	Avalanche Current	86	A
P₀@T₀=25℃	Total Power Dissipation ⁴	78	W
T _{STG}	Storage Temperature Range	-55 to 175	°C
TJ	Operating Junction Temperature Range	-55 to 175	°C

Thermal Data

Symbol	Parameter		Max.	Unit
R _{ejA}	Thermal Resistance Junction-Ambient ¹		55	°C/W
R _{θJC}	Thermal Resistance Junction-Case ¹		1.6	°C/W





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Electrical Characteristics (T_J=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =250uA	30			V
$\triangle BV_{DSS} / \triangle T_J$	BV _{DSS} Temperature Coefficient	Reference to 25 $^\circ\!\mathrm{C}$, I_D=1mA		0.022		V/℃
D	Static Drain-Source On-Resistance ²	V _{GS} =10V , I _D =20A		2.2	3.5	
R _{DS(ON)}		V _{GS} =4.5V , I _D =15A		3.1	4.2	mΩ
V _{GS(th)}	Gate Threshold Voltage		1.2	1.6	2.5	V
	V _{GS(th)} Temperature Coefficient	— V _{GS} =V _{DS} , I _D =250uA		-6.1		mV/℃
	Drain Source Lookage Current	V _{DS} =24V , V _{GS} =0V , T _J =25℃			2	
I _{DSS}	Drain-Source Leakage Current	V _{DS} =24V , V _{GS} =0V , T _J =55℃			10	uA
I _{GSS}	Gate-Source Leakage Current	$V_{GS}=\pm20V$, $V_{DS}=0V$			±100	nA
gfs	Forwar Trd ansconductance	V _{DS} =5V , I _D =15A		32		S
Rg	Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz		1.1	2.5	Ω
Qg	Total Gate Charge (4.5V)			22		nC
Q _{gs}	Gate-Source Charge			4.3		
Q _{gd}	Gate-Drain Charge			8.3		
T _{d(on)}	Turn-On Delay Time			11		
Tr	Rise Time Rise Time	V _{DD} =15V , V _{GEN} =10V , R _G =6Ω, I _D =1A, RL=15Ω.		16		n 0
T _{d(off)}	Turn-Off Delay Time			35		ns
T _f	Turn-Off Fall Time			40		
Ciss	Input Capacitance			2450		
C _{oss}	Output Capacitance	V _{DS} =15V , V _{GS} =0V , f=1MHz		590		pF
C _{rss}	Reverse Transfer Capacitance			245		

Guaranteed Avalanche Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
EAS	Single Pulse Avalanche Energy ⁵	V _{DD} =25V , L=0.1mH , I _{AS} =15A	85			mJ

Diode Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current ^{1,6}	$V_G = V_D = 0V$, Force Current			50	А
I _{SM}	Pulsed Source Current ^{2,6}				310	А
V _{SD}	Diode Forward Voltage ²	$V_{GS}\text{=}0V$, $I_{S}\text{=}20A$, $T_{J}\text{=}25^{\circ}\!\!\mathbb{C}$			1.2	V

Note :

1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper,t<10sec.

2. The data tested by pulsed , pulse width \leq 300us , duty cycle \leq 2%

3. The EAS data shows Max. rating . The test condition is V_{DD}=25V,V_{GS}=10V,L=0.1mH,I_{AS}=20A

4. The power dissipation is limited by 150 °C junction temperature

5. The Min. value is 100% EAS tested guarantee.

6. The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation.

7.Package limitation current is 100A.



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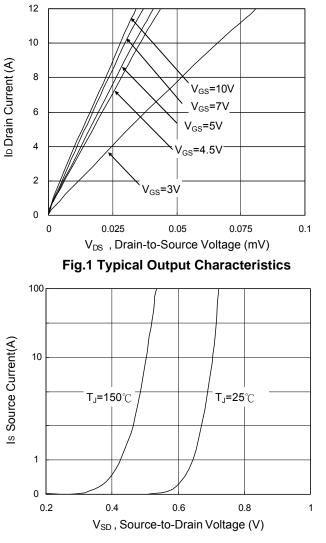
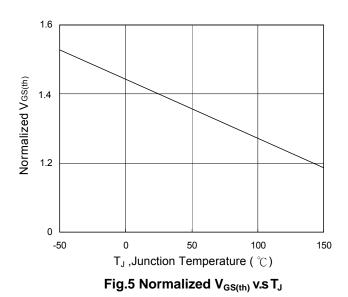


Fig.3 Forward Characteristics of Reverse



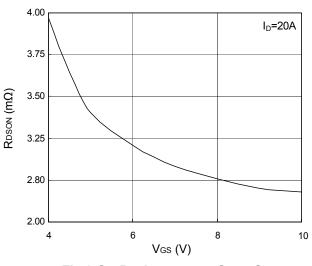


Fig.2 On-Resistance v.s Gate- Source

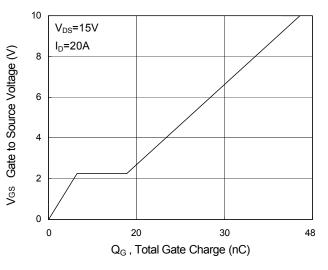


Fig.4 Gate-Charge Characteristics

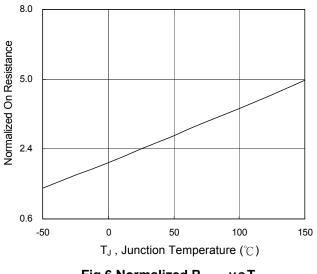


Fig.6 Normalized R_{DSON} v.s T_J



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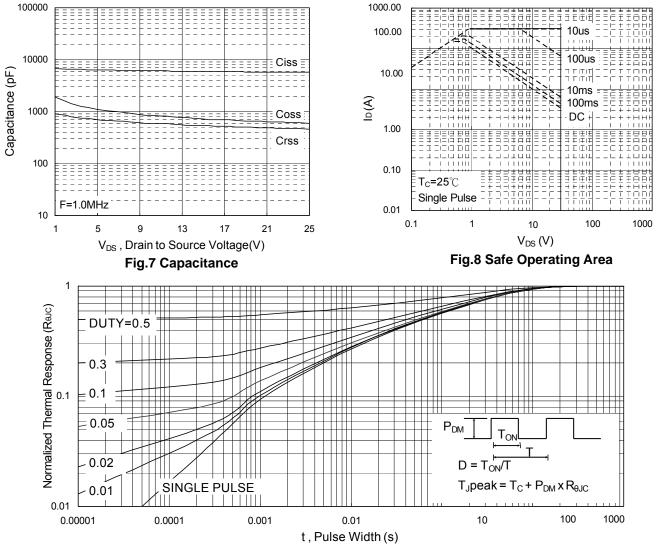
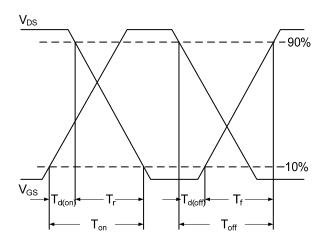


Fig.9 Normalized Maximum Transient Thermal Impedance





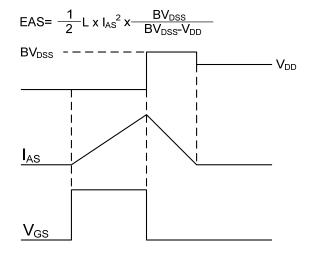


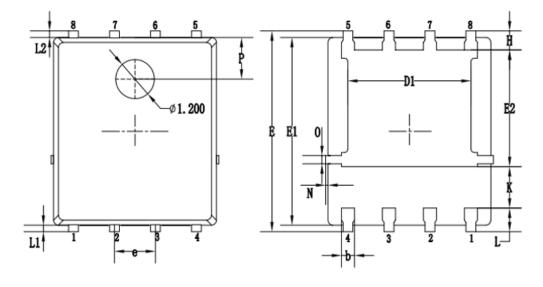
Fig.11 Unclamped Inductive Waveform

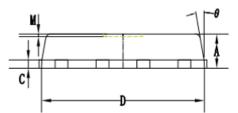


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Packaging information





		MILLIMETERS			
SYMBOLS	MIN.	NOM.	MAX.		
A	0.90	1.05	1.20		
b	0.35	0.40	0.50		
С	0.20	0.25	0.35		
D	4.90	5.05	5.20		
D1	3.72	3.82	3.92		
E	6.00	6.15	6.30		
E1	5.60	5.75	5.90		
E2	3.47	3.57	3.67		
е		1.27 BSC.			
Н	0.48	0.58	0.68		
К	1.17	1.27	1.37		
L	0.64	0.74	0.84		
L1/L2		0.20 REF.			
θ	8°	10° 12°			
М		0.08 REF.			
N	0	-	0.15		
0		0.25 REF.			
Р		1.28 REF.			



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